

Search Notes

Application/Control No.

10/657,350

Examiner

Sin J. Lee

Applicant(s)/Patent under
Reexamination

BOYKIN ET AL.

Art Unit

1752

SEARCHED

Class	Subclass	Date	Examiner
430	270.1	5-1-05	SJL
↓	273.1	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR